

Notice of References Cited	Application/Control No. 10/616,548	Applicant(s)/Patent Under Reexamination BALDWIN ET AL.	
	Examiner Michael P. Stafira	Art Unit 2877	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2004/0001059	01-2004	Pfister et al.	345/419
	C	US-2002/0080136	06-2002	Kouadio, Cyriaque	345/426
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	E	US-2003/0179371	09-2003	Rangarajan et al.	356/237.2
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NON-PATENT DOCUMENTS

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	U	James Jafolla, "Theory and measurement of bidirectional reflectance for signature analysis", 1999, SPIE Vol. 3699.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.